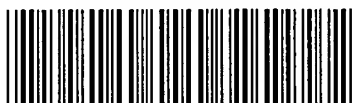


**Search Notes**

Application/Control No.

10/646,708

Examiner

Patrick J. Lee

Applicant(s)/Patent under  
Reexamination

ECKER ET AL.

Art Unit

2878

**SEARCHED**

Class	Subclass	Date	Examiner
250	227.14, 227.16	8/9/2005	PL
385	10, 12	8/9/2005	PL
385	13, 37	8/9/2005	PL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted w/ S. Allen	8/4/2005	PL
Consulted w/ B. Healy AU 2883 CL 385	8/9/2005	PL
East (See attached)	8/9/2005	PL